Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10653791	OHBA, AKIO	
Examiner	Art Unit	
Repko, Jason M	2628	

SEARCHED					
Subclass	Date	Examiner			

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST text search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB see search history printout	11/7/2006	JMR		
Consulted Examiners in QEM 2628: Kimbinh Nguyen, Dan Hajnik, Andrew Yang, Crystal Murdoch	11/9/2006	JMR		

INTERFERENCE SEARCH				
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